

Notice of References Cited	Application/Control No. 10/697,321		Applicant(s)/Patent Under Reexamination YOSHIDA ET AL.	
	Examiner Toan M Le		Art Unit 2863	Page 1 of 1

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	B	US-5,734,713	03-1998	Mauney et al.	379/395
	C	US-5,812,084	09-1998	Bonanni et al.	342/352
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NON-PATENT DOCUMENTS

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	W	Muller et al., Optimized 1 V and 10 V Josephson Series Arrays, April 1997, IEEE Transactions on Instrumentation and Measurement, Vol. 46, No. 2, Pages 229-232
	X	Hale et al., Frequency Response Metrology for High-Speed Optical Receivers, National Institute of standards and technology, date unknown

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.